

Cooling NI Single-Board RIO Systems

Appendix: Reference Examples
NI sbRIO-9623/26/33/36

6/28/2012



1.	NI sbRIO-9626 General Setup	3
2.	Example A – NI sbRIO-9626, Open Air vs. Enclosure Size	6
3.	Example B – NI sbRIO-9626, Open Air vs. Enclosure Size, With RMC	9
4.	Example C – NI sbRIO-9626, Open Air vs. Enclosure Size, With Thermal Solution	15
5.	Example D – NI sbRIO-9626, Open Air vs. Enclosure Size, With Thermal Solution and RMC	19

1. NI sbRIO-9626 General Setup

Device Under Test (DUT): NI sbRIO-9626

Equipment and Testing Supplies:

Test Equipment:

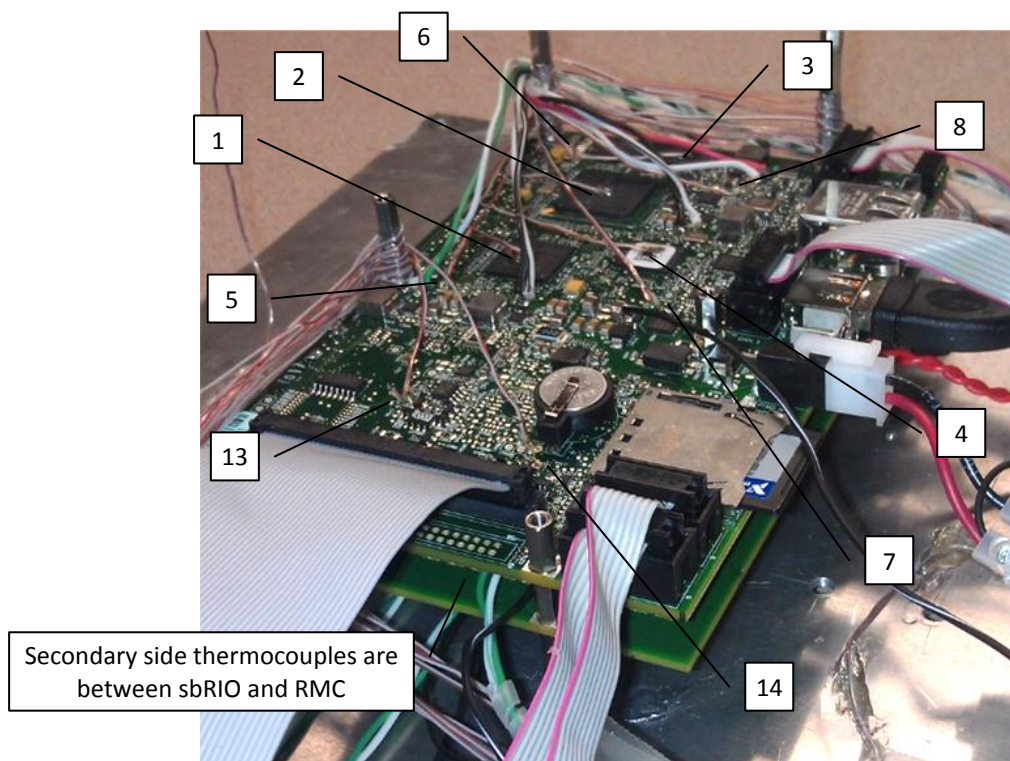
- NI sbRIO-9626 Power Cable (NI P/N 152834-01)
- I/O Connectors and Cables
- RMC Resistor Load Test Board (used to simulate added power from an RMC)
- Heat spreader (NI P/N 153901-01)

Enclosures:

- Large Fiberglass Enclosure – 12.0"x10.0"x6.34"
- Aluminum Panel (To mount the NI sbRIO-9626 for open air and inside the large enclosure)
- Small Plastic Enclosure with plastic mounting panel – 9.5"x6.3"x2.5"
- Small Metal Enclosure – 10.2"x6.3"x3.6"

NI sbRIO-9626 DUT Preparation:

- Thermocouples were mounted to critical ICs per user manual
- Four local ambient thermocouples were mounted approximately 0.2" away from the PCB on either side of the NI sbRIO-9626
- Wires were connected in order to measure the power dissipated by the FPGA



RMC Resistor Load Test Board Preparation:

- 4.05"x6.05" PCB
- Load resistors to provide even power distribution on both sides of PCB (e.g. 3W RMC test board is 1.5W on each side)

Software:

- A system stress and verify VI is run
 - Stresses the processor and FPGA to max achievable power
 - Performs write, read back, and verify tests to a USB Flash drive, DDR2 memory, and the NAND flash
 - Stresses and verifies I/O

Measurements:

The following table provides the channel, name, and description of the thermocouples that were measured during the tests, as well as the maximum allowed temperature for critical ICs and ambient locations for the NI sbRIO-9626 as defined in the user manual.

Channel	Name	Description	Max Allowed (°C)	Comments
1	T _{C-FPGA}	FPGA Case	93	
2	T _{C-Proc}	Processor Case	106.9	
3	T _{C-DDR}	DDR Case	97	Measuring one chip. Tests showed both were equal
4	T _{C-NAND}	NAND Case	89.9	
5	T _{A-P-TM}	Primary Side, Top Middle Local Ambient	85	Mounted 0.2" off PCB
6	T _{A-P-TR}	Primary Side, Top Right Local Ambient	85	Mounted 0.2" off PCB
7	T _{A-P-BM}	Primary Side, Bottom Middle Local Ambient	85	Mounted 0.2" off PCB
8	T _{A-P-BR}	Primary Side, Bottom Right Local Ambient	85	Mounted 0.2" off PCB
9	T _{A-S-TM}	Secondary Side, Top Middle Local Ambient	85	Mounted 0.2" off PCB
10	T _{A-S-TR}	Secondary Side, Top Right Local Ambient	85	Mounted 0.2" off PCB
11	T _{A-S-BM}	Secondary Side, Bottom Middle Local Ambient	85	Mounted 0.2" off PCB
12	T _{A-S-BR}	Secondary Side, Bottom Right Local Ambient	85	Mounted 0.2" off PCB
13	T _{A-P-TL}	Primary Side, Top Left Local Ambient	85	Mounted 0.2" off PCB
14	T _{A-P-BL}	Primary Side, Bottom Left Local Ambient	85	Mounted 0.2" off PCB
15	T _{A-S-TL}	Secondary Side, Top Left Local Ambient	85	Mounted 0.2" off PCB
16	T _{A-S-BL}	Secondary Side, Bottom Left Local Ambient	85	Mounted 0.2" off PCB
17	T _{A-Encl-1}	Enclosure Internal Ambient (Away from PCB)	NA	Only monitored when using an enclosure
18	T _{A-Encl-2}	Enclosure Internal Ambient (Away from PCB)	NA	
	T _{A-Ext}	External Ambient (Room Ambient)	NA	Average of two thermocouple measurements

Note: IC case temperatures were either obtained from manufacturer's datasheets or calculated using the formula:

$$T_J = T_C + P \times \Theta_{J-C}$$

Where:

T_J – Junction Temperature

T_C – Case Temperature

P – Power Dissipation (From Datasheet, Measured or Estimated)

Θ_{J-C} – Junction-Case Thermal Resistance

Test Procedure:

- Testing was conducted at room temperature
- The NI sbRIO-9626 was mounted as described by the examples in the following sections
- The NI sbRIO-9626 was powered at 9V
- The system stressing VI was configured and run
- The system was allowed to reach steady state
- Temperature measurements were logged

2. Example A – NI sbRIO-9626, Open Air vs. Enclosure Size

2.1. Test Description

In this example, the NI sbRIO-9626 was configured in open air and with varying enclosure sizes to show how the enclosure size affects the self-heating around the circuit card.

2.2. Test Results Summary

The self-heating within an enclosure increases as the enclosure size decreases, resulting in a lower achievable external ambient.

In this set of examples, without a thermal solution, the FPGA has the lowest margin. Extrapolating to the maximum allowed case temperature of the FPGA, the estimated maximum achievable external ambient for each configuration is shown in the following table.

Configuration	A (Open Air)	B (Large Fiberglass Enclosure)	C (Small Plastic Enclosure)
Max Achievable T_{A-Ext} (°C)	61.2	57.1	52.1

In addition, because there was a large difference between the margin of the FPGA and the next lowest margin temperature measurement, less stressful applications or the addition of a thermal solution such as a heat sink or heat spreader may improve the max achievable external ambient. Later in this document, examples showing the impact of adding a thermal solution will be examined. See Examples C and D for more information.

2.3. Test Setup

In this example, the NI sbRIO-9626 was installed without an RMC (i.e. controller only).

- The NI sbRIO-9626 was mounted to the panel using 9.65mm standoffs.
- (A) Open Air Configuration – The NI sbRIO-9626 was mounted to a metal panel and oriented vertically, as shown in the following images.
- (B) Large Fiberglass Enclosure – The NI sbRIO-9626 was mounted to a metal panel and installed into a large fiberglass enclosure. The enclosure was oriented such that the PCB was vertical during testing, as shown in the following images.
- (C) Small Plastic Enclosure – The NI sbRIO-9626 was mounted to a plastic panel and installed into a small plastic enclosure. The enclosure was oriented such that the PCB was vertical during testing, as shown in the following images.

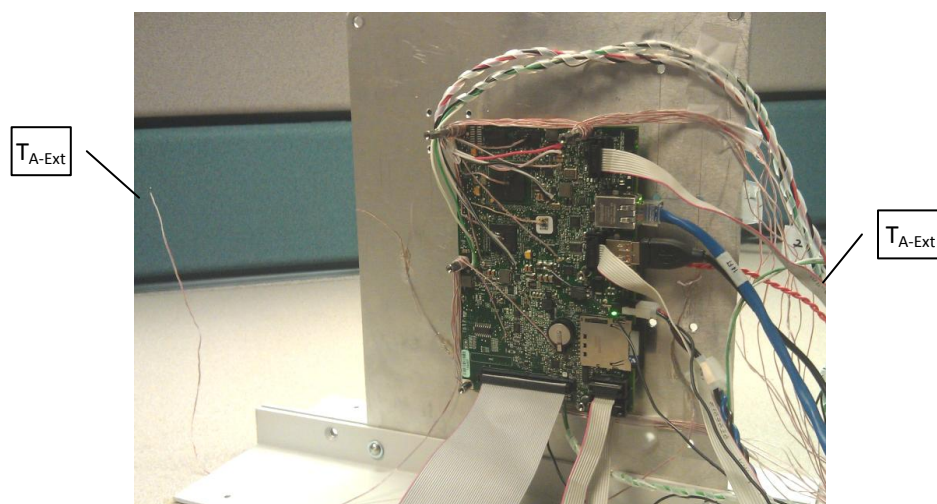


Figure 1: Configuration A – NI sbRIO-9626 in open air

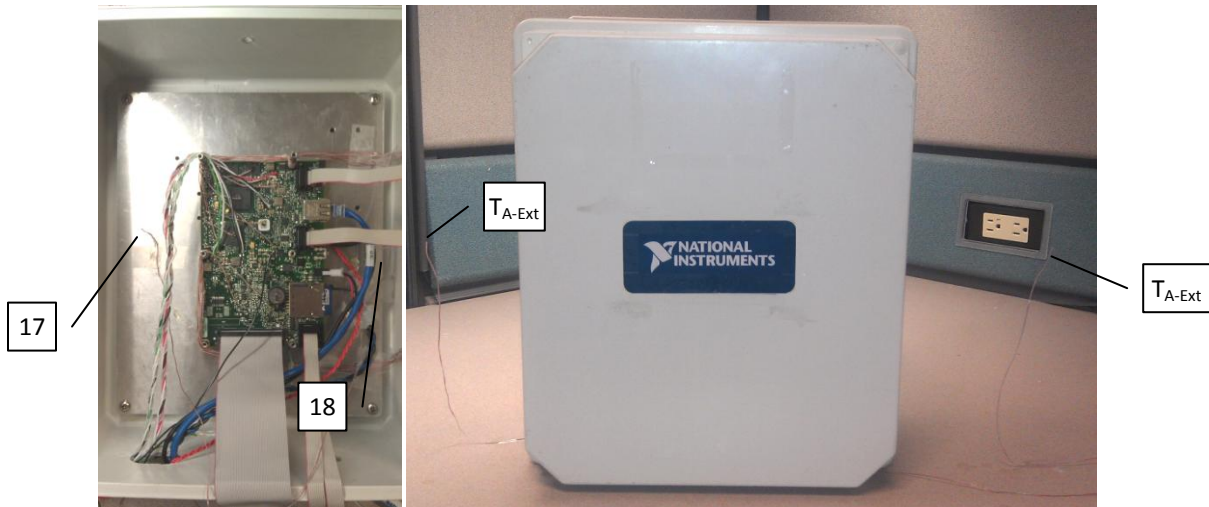


Figure 2: Configuration B – NI sbRIO-9626 in a large fiberglass enclosure

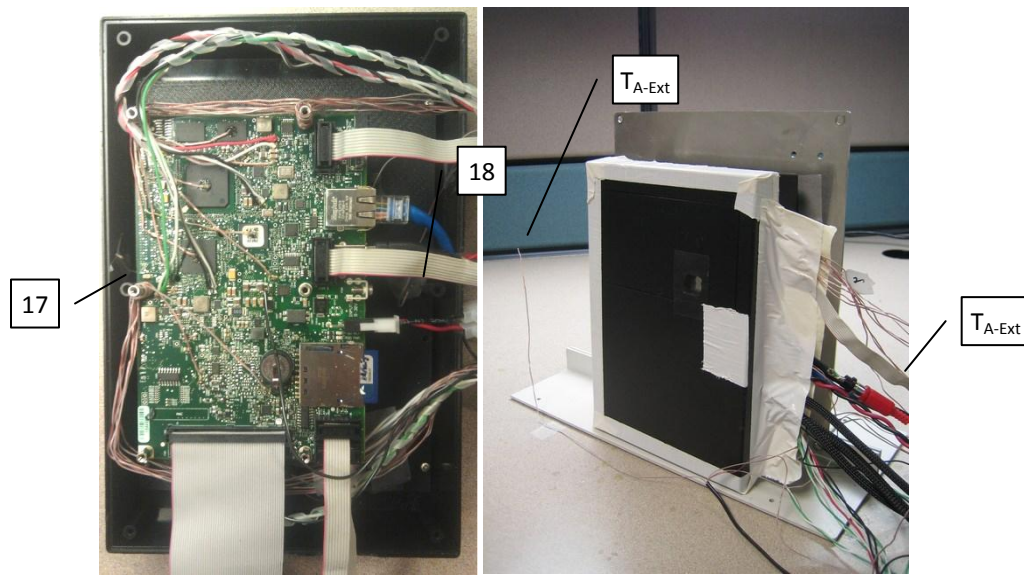


Figure 3: Configuration C – NI sbRIO-9626 in a small plastic enclosure

2.4. Results

The following table shows the test results normalized to $T_{A-Ext}=25^{\circ}\text{C}$. In addition, it includes the margin of the temperature reading compared to the maximum allowed values for each component or ambient measurement. In the "margin" column, the lowest margin component is highlighted.

Channel	Name	A Open Air		B Large Fiberglass Encl.		C Small Plastic Encl.	
		Measurement (°C)	Margin (°C)	Measurement (°C)	Margin (°C)	Measurement (°C)	Margin (°C)
1	T _{C-FPGA}	56.8	36.2	60.9	32.1	65.9	27.1
2	T _{C-Proc}	51.5	55.4	55.8	51.1	61.3	45.6
3	T _{C-DDR}	46.2	50.8	50.3	46.7	56.0	41.0
4	T _{C-NAND}	43.4	46.5	47.4	42.5	52.3	37.6
5	T _{A-P-TM}	38.2	46.8	42.6	42.4	47.7	37.3
6	T _{A-P-TR}	40.2	44.8	45.9	39.1	51.9	33.1
7	T _{A-P-BM}	38.6	46.4	42.1	42.9	47.1	37.9
8	T _{A-P-BR}	40.0	45.0	44.3	40.7	50.4	34.6
9	T _{A-S-TM}	39.0	46.0	43.6	41.4	48.7	36.3
10	T _{A-S-TR}	41.5	43.5	45.6	39.4	52.4	32.6
11	T _{A-S-BM}	40.2	44.8	44.0	41.0	48.9	36.1
12	T _{A-S-BR}	41.5	43.5	45.5	39.5	51.7	33.3
13	T _{A-P-TL}	35.5	49.5	38.6	46.4	42.2	42.8
14	T _{A-P-BL}	35.2	49.8	38.2	46.8	41.9	43.1
15	T _{A-S-TL}	36.7	48.3	39.5	45.5	43.1	41.9
16	T _{A-S-BL}	36.6	48.4	39.0	46.0	42.7	42.3
17	T _{A-Encl-1}	-	-	28.6	-	35.9	-
18	T _{A-Encl-2}	-	-	29.4	-	34.5	-
	T _{A-Ext}	25.0	-	25.0	-	25.0	-

The measured system power draw of the NI sbRIO-9626 was 8.3W for each configuration.

The first thing to note is that the FPGA has the lowest margin in all three configurations. Also, the self-heating caused by the addition of an enclosure results in an additional temperature rise within the system.

Comparing B to A, the added self-heating temperature rise of the larger fiberglass enclosure is approximately 3 to 5°C. Comparing C to A, the added self-heating of the small plastic enclosure is approximately 7 to 11°C.

Using this data, we can estimate the maximum achievable external ambient for each configuration, as shown in the following table.

Configuration	A	B	C
Max Achievable T _{A-Ext} (°C)	61.2	57.1	52.1

In addition, looking at the internal enclosure ambient measurements (T_{A-Encl}), these measurements may not be directly compared to one another because their relative location to the PCB differs. However, this does demonstrate that using an internal enclosure measurement away from the circuit board may not accurately predict differences seen by the components inside the enclosure.

3. Example B – NI sbRIO-9626, Open Air vs. Enclosure Size, With RMC

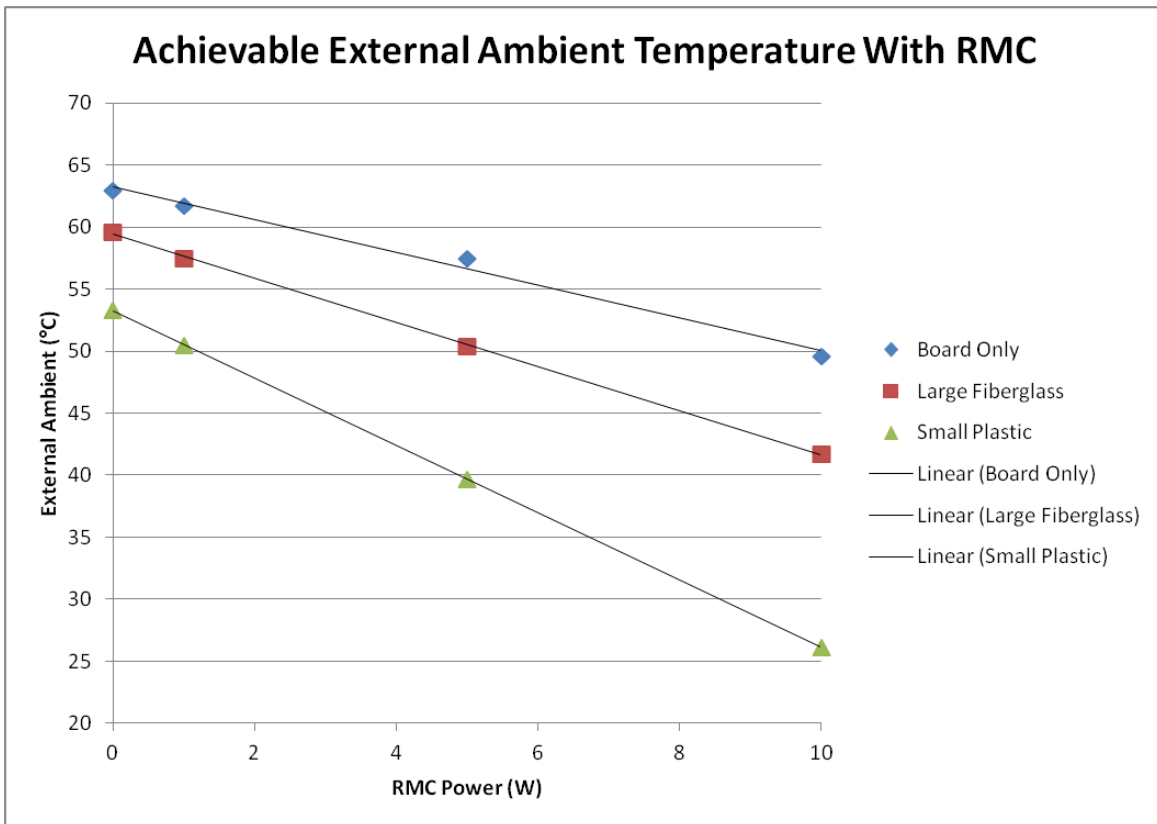
3.1. Test Description

In this example, the NI sbRIO-9626 was configured with an RMC, loaded at varying power levels to show the impact of adding an expansion card. The same open air and enclosure configurations from Example A were used.

3.2. Test Results Summary

The self-heating within an enclosure increases as the enclosure size decreases, resulting in a lower achievable external ambient. In addition, the rate of self-heating increases with increasing RMC power as the enclosure size decreases, resulting in a larger change in the achievable external ambient between the 0W RMC and 10W RMC with a smaller enclosure.

In this set of examples, without a thermal solution, the FPGA has the lowest margin. Extrapolating to the maximum allowed case temperature of the FPGA, the estimated maximum achievable external ambient for each configuration is shown in the following chart.



In addition, because there was a large difference between the margin of the FPGA and the next lowest margin temperature measurement, less stressful applications or the addition of a thermal solution such as a heat sink or heat spreader may improve the max achievable external ambient. Later in this document, examples showing the impact of adding a thermal solution will be examined. See Examples C and D for more information.

3.3. Test Setup

In this example, the NI sbRIO-9626 was installed with a resistor load RMC test board.

- The circuit cards were mounted such that the RMC was between the mounting panel and the NI sbRIO-9626.

- The RMC was mounted to the panel using standoffs. The standoffs were doubled to clear test connectors underneath the RMC test board, resulting in a total standoff distance of 19.3mm between the RMC and panel.
- The NI sbRIO-9626 was mounted to the RMC using 9.65mm standoffs.
- The same open air and enclosure configurations as in Example A were used.
- Tests were performed with the RMC load at 0W, 1W, 5W, and 10W. In the test results, the subscript number for each test configuration corresponds to the RMC power load used for that test. So, A_0 corresponds to the unpowered, 0W RMC, A_1 corresponds to the 1W RMC, as so on.
- (A) Open Air Configuration – The NI sbRIO-9626 with RMC was mounted to a metal panel and oriented vertically, as shown in the following images.
- (B) Large Fiberglass Enclosure – The NI sbRIO-9626 with RMC was mounted to a metal panel and installed into a large fiberglass enclosure. The enclosure was oriented such that the PCB was vertical during testing, as shown in the following images.
- (C) Small Plastic Enclosure – The NI sbRIO-9626 with RMC was mounted to a plastic panel and installed into a small plastic enclosure. The enclosure was oriented such that the PCB was vertical during testing, as shown in the following images.

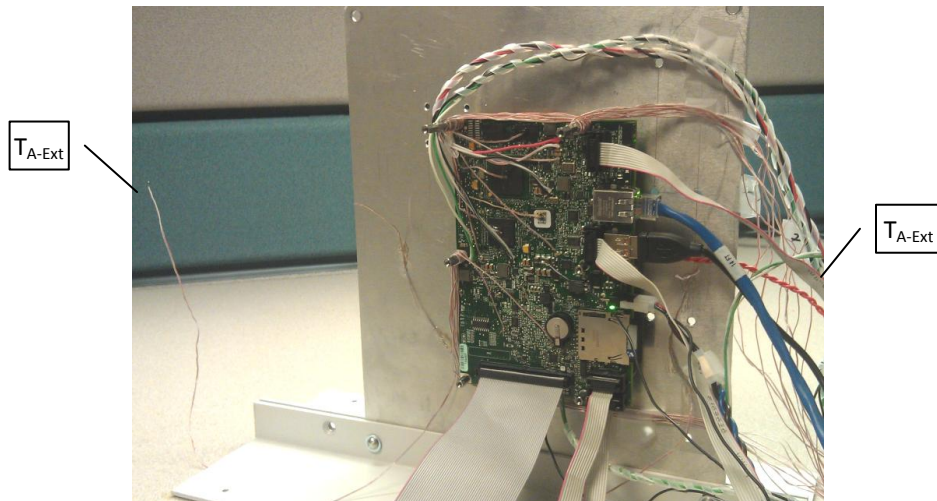


Figure 4: Configuration A – NI sbRIO-9626 with RMC test board in open air

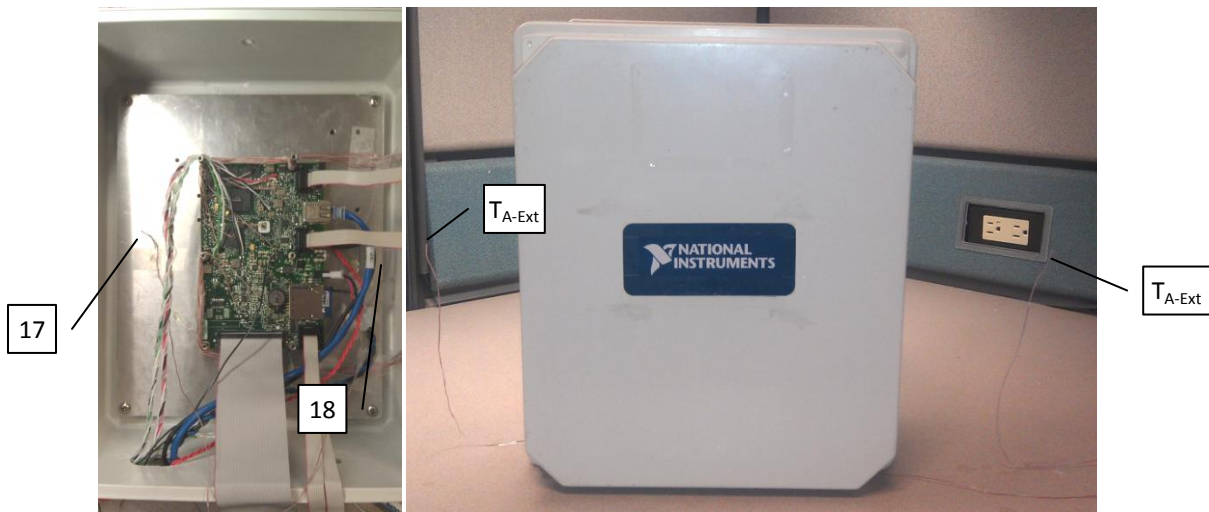


Figure 5: Configuration B – NI sbRIO-9626 with RMC test board in a large fiberglass enclosure

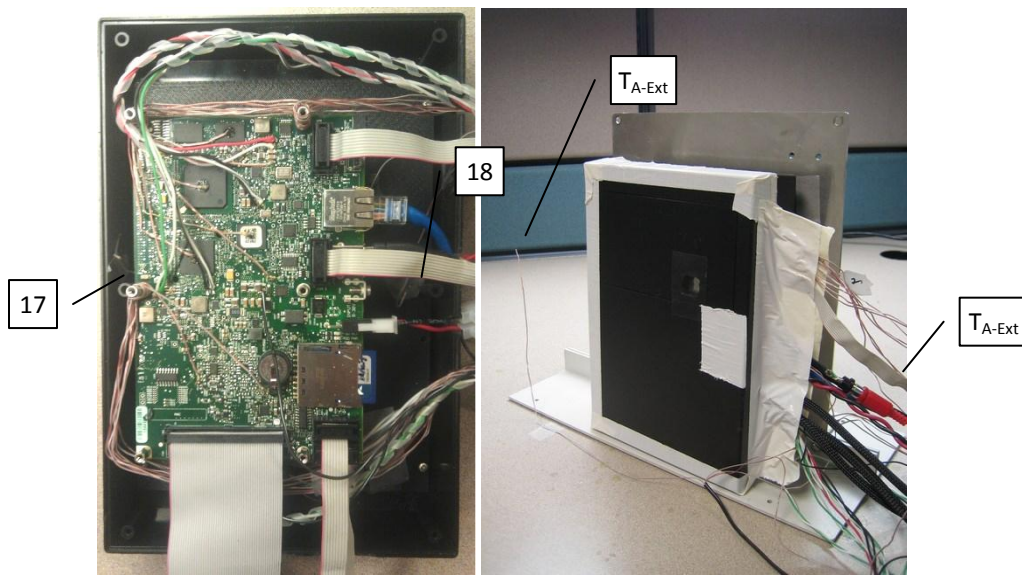


Figure 6: Configuration C – NI sbRIO-9626 with RMC test board in a small plastic enclosure

3.4. Results

The following table shows the test results normalized to $T_{A-Ext}=25^{\circ}\text{C}$. It includes the power draw measured by both the sbRIO board and the RMC test board, along with the margin of the temperature reading compared to the maximum allowed values for each component or ambient measurement. In the "margin" column, the lowest margin component is highlighted.

Configuration A – Open Air with RMC

Configuration		A_0		A_1		A_5		A_{10}	
NI sbRIO-9626 Power (W)		8.5		8.6		9.1		10.0	
RMC Power (W)		0.0		1.0		5.0		10.0	
Total System Power (W)		8.5		9.6		14.1		20.0	
Channel	Name	Measurement ($^{\circ}\text{C}$)	Margin ($^{\circ}\text{C}$)	Measurement ($^{\circ}\text{C}$)	Margin ($^{\circ}\text{C}$)	Measurement ($^{\circ}\text{C}$)	Margin ($^{\circ}\text{C}$)	Measurement ($^{\circ}\text{C}$)	Margin ($^{\circ}\text{C}$)
1	T_{C-FPGA}	55.0	38.0	56.3	36.7	60.5	32.5	68.4	24.6
2	T_{C-Proc}	49.6	57.3	50.8	56.1	55.0	51.9	61.2	45.7
3	T_{C-DDR}	44.6	52.4	45.8	51.2	49.9	47.1	55.8	41.2
4	T_{C-NAND}	42.1	47.8	43.3	46.6	47.6	42.3	54.0	35.9
5	T_{A-P-TM}	37.3	47.7	38.2	46.8	41.4	43.6	45.7	39.3
6	T_{A-P-TR}	38.4	46.6	39.5	45.5	43.2	41.8	47.8	37.2
7	T_{A-P-BM}	37.8	47.2	38.9	46.1	42.5	42.5	48.3	36.7
8	T_{A-P-BR}	39.1	45.9	39.7	45.3	43.0	42.0	47.1	37.9
9	T_{A-S-TM}	37.9	47.1	39.4	45.6	42.4	42.6	47.8	37.2
10	T_{A-S-TR}	40.3	44.7	42.1	42.9	46.4	38.6	53.3	31.7
11	T_{A-S-BM}	39.4	45.6	41.6	43.4	47.2	37.8	55.2	29.8
12	T_{A-S-BR}	40.9	44.1	43.0	42.0	48.2	36.8	55.5	29.5

13	T _{A-P-TL}	34.9	50.1	35.3	49.7	37.5	47.5	41.2	43.8
14	T _{A-P-BL}	34.6	50.4	35.0	50.0	37.6	47.4	41.8	43.2
15	T _{A-S-TL}	36.1	48.9	36.6	48.4	39.8	45.2	44.1	40.9
16	T _{A-S-BL}	36.0	49.0	36.6	48.4	40.7	44.3	45.9	39.1
	T _{A-Ext}	25.0	-	25.0	-	25.0	-	25.0	-

Configuration B – Large Fiberglass Enclosure with RMC

Configuration		B ₀		B ₁		B ₅		B ₁₀	
NI sbRIO-9626 Power (W)		8.3		8.3		8.9		9.9	
RMC Power (W)		0.0		1.0		5.0		10.0	
Total System Power (W)		8.3		9.3		13.9		19.9	
Channel	Name	Measurement (°C)	Margin (°C)	Measurement (°C)	Margin (°C)	Measurement (°C)	Margin (°C)	Measurement (°C)	Margin (°C)
1	T _{C-FPGA}	58.4	34.6	60.5	32.5	67.6	25.4	76.3	16.7
2	T _{C-Proc}	53.1	53.8	55.2	51.7	62.4	44.5	70.8	36.1
3	T _{C-DDR}	48.0	49.0	50.0	47.0	57.0	40.0	65.1	31.9
4	T _{C-NAND}	45.5	44.4	47.4	42.5	54.5	35.4	63.1	26.8
5	T _{A-P-TM}	40.9	44.1	42.5	42.5	48.2	36.8	54.9	30.1
6	T _{A-P-TR}	43.2	41.8	45.1	39.9	51.8	33.2	59.4	25.6
7	T _{A-P-BM}	41.1	43.9	42.9	42.1	49.3	35.7	57.4	27.6
8	T _{A-P-BR}	42.9	42.1	44.6	40.4	50.6	34.4	57.6	27.4
9	T _{A-S-TM}	41.9	43.1	43.8	41.2	50.5	34.5	58.5	26.5
10	T _{A-S-TR}	44.0	41.0	46.2	38.8	54.1	30.9	63.2	21.8
11	T _{A-S-BM}	42.7	42.3	45.1	39.9	53.9	31.1	64.8	20.2
12	T _{A-S-BR}	44.3	40.7	46.7	38.3	55.3	29.7	65.6	19.4
13	T _{A-P-TL}	37.7	47.3	39.0	46.0	43.6	41.4	49.2	35.8
14	T _{A-P-BL}	37.4	47.6	38.6	46.4	43.4	41.6	49.2	35.8
15	T _{A-S-TL}	38.9	46.1	40.3	44.7	45.7	39.3	52.3	32.7
16	T _{A-S-BL}	38.5	46.5	40.0	45.0	45.8	39.2	52.8	32.2
17	T _{A-Encl-1}	28.8	-	29.8	-	32.7	-	35.7	-
18	T _{A-Encl-2}	29.5	-	30.5	-	33.5	-	36.5	-
	T _{A-Ext}	25.0	-	25.0	-	25.0	-	25.0	-

Configuration C – Small Plastic Enclosure with RMC

Configuration		C ₀		C ₁		C ₅		C ₁₀	
NI sbRIO-9626 Power (W)		8.3		8.4		8.9		10.2	
RMC Power (W)		0.0		1.0		5.0		10.0	
Total System Power (W)		8.3		9.4		13.9		20.2	

Channel	Name	Measurement (°C)	Margin (°C)	Measurement (°C)	Margin (°C)	Measurement (°C)	Margin (°C)	Measurement (°C)	Margin (°C)
1	T _{C-FPGA}	64.7	28.3	67.5	25.5	78.3	14.7	91.9	1.1
2	T _{C-Proc}	59.9	47.0	62.8	44.1	74.1	32.8	87.7	19.2
3	T _{C-DDR}	54.9	42.1	57.7	39.3	68.6	28.4	81.8	15.2
4	T _{C-NAND}	51.8	38.1	54.6	35.3	65.4	24.5	79.1	10.8
5	T _{A-P-TM}	47.3	37.7	49.8	35.2	59.4	25.6	71.1	13.9
6	T _{A-P-TR}	50.3	34.7	53.2	31.8	63.9	21.1	76.7	8.3
7	T _{A-P-BM}	47.1	37.9	49.9	35.1	60.3	24.7	73.5	11.5
8	T _{A-P-BR}	50.5	34.5	53.4	31.6	64.0	21.0	76.8	8.2
9	T _{A-S-TM}	47.9	37.1	50.7	34.3	61.2	23.8	74.2	10.8
10	T _{A-S-TR}	50.7	34.3	53.8	31.2	65.5	19.5	79.5	5.5
11	T _{A-S-BM}	48.5	36.5	51.7	33.3	64.1	20.9	79.8	5.2
12	T _{A-S-BR}	50.9	34.1	54.1	30.9	66.5	18.5	81.6	3.4
13	T _{A-P-TL}	42.4	42.6	44.5	40.5	52.4	32.6	62.0	23.0
14	T _{A-P-BL}	42.3	42.7	44.4	40.6	52.3	32.7	62.1	22.9
15	T _{A-S-TL}	43.4	41.6	45.7	39.3	54.3	30.7	64.7	20.3
16	T _{A-S-BL}	43.0	42.0	45.5	39.5	54.5	30.5	65.4	19.6
17	T _{A-Encl-1}	37.1	-	39.4	-	47.1	-	56.4	-
18	T _{A-Encl-2}	34.5	-	36.2	-	42.7	-	50.1	-
	T _{A-Ext}	25.0	-	25.0	-	25.0	-	25.0	-

The tests above shown with a 0W RMC had the RMC board installed, but not powered. The measured power draw of the NI sbRIO-9626 increases slightly as the RMC power increases due to the added load on the power supply. With a 10W RMC, this results in 1.5 to 2W of additional power being dissipated on the sbRIO board.

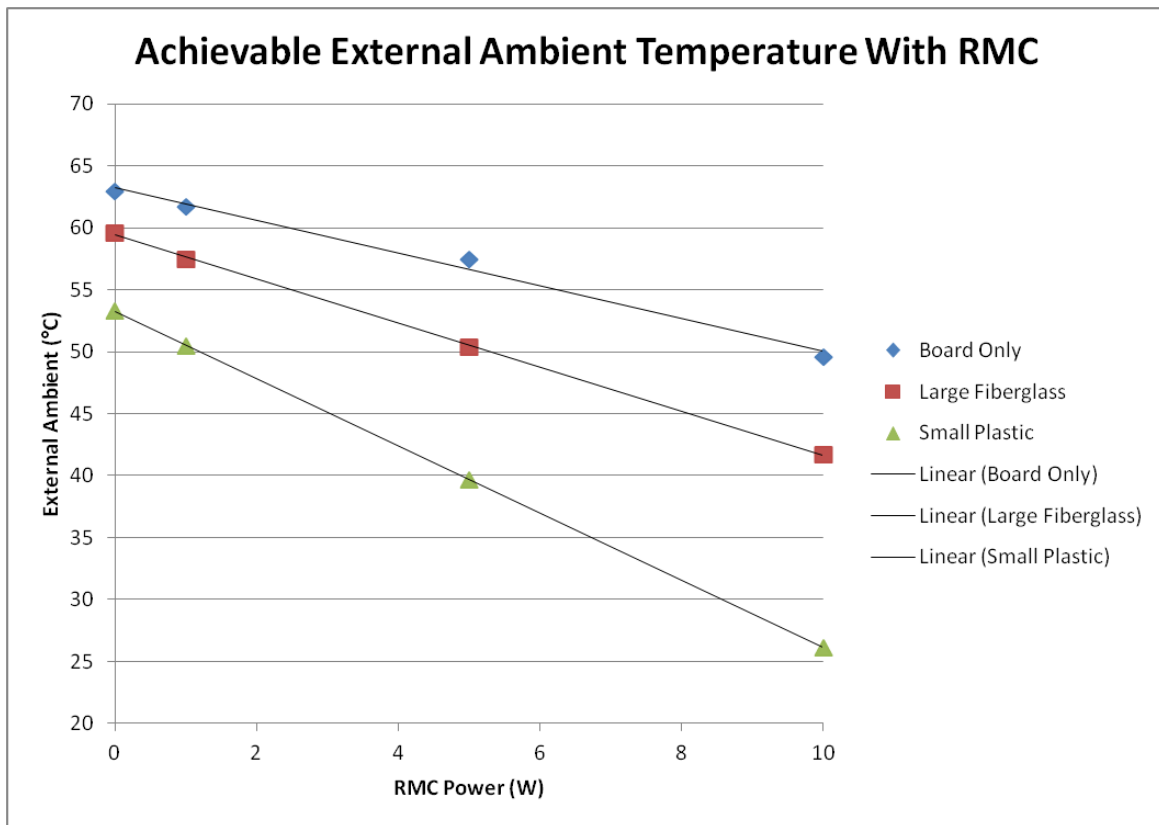
The first thing to note is that the FPGA has the lowest margin in all three configurations. Also, the self-heating caused by the addition of an enclosure results in an additional temperature rise within the system.

It is also seen that the local ambient temperatures on the secondary side of the sbRIO board, between the sbRIO and RMC (T_{A-S-XX}) are typically hotter than the local ambient temperature measurements on the primary side. This becomes more noticeable as the RMC power increases.

Using this data, the maximum achievable external ambient for each configuration is estimated, as shown in the following table.

RMC Power (W)	Max Achievable T _{A-Ext} (°C)		
	A	B	C
0.0	63.0	59.6	53.3
1.0	61.7	57.5	50.5
5.0	57.5	50.4	39.7
10.0	49.6	41.7	26.1

The following chart plots the achievable external ambient compared with RMC power levels for each configuration. The results may be approximated with a linear extrapolation to estimate the ambient at different RMC power levels within the different enclosures.



4. Example C – NI sbRIO-9626, Open Air vs. Enclosure Size, With Thermal Solution

4.1. Test Description

In this example, the NI sbRIO-9626 was configured with a heat spreader and installed in open air and with varying enclosure sizes/materials to show how a heat spreader can improve the thermal performance.

4.2. Test Results Summary

With the addition of a heat spreader, the impact of self-heating is greatly reduced compared to the tests in Example A. In addition, the heat spreader greatly reduces the case temperature of the FPGA and other critical ICs, making the local ambient temperatures around the PCB the lowest margin, resulting in a higher external ambient temperature. Extrapolating to the maximum allowed local ambient temperature of the lowest margin region (T_{A-P-BR}), the estimated maximum achievable external ambient for each configuration is shown in the following table.

Configuration	A (Open Air)	B (Large Fiberglass Enclosure)	D (Small Metal Enclosure)
Max Achievable T_{A-Ext} (°C)	73.1	69.0	70.3

Comparing to Example A, configurations A and B result in approximately 12°C increase in the achievable external ambient. Comparing configuration C (Example A) to configuration D in this example there is approximately 18°C increase in the achievable external ambient by changing from a small plastic enclosure to a small metal enclosure with a heat spreader.

4.3. Test Setup

- In this example, the NI sbRIO-9626 was installed with a heat spreader attached (NI P/N 153901-01). No RMC was installed (i.e. controller only).
- The NI sbRIO-9626 was mounted such that the heat spreader directly contacted the metal mounting surface.
- (A) Open Air Configuration – The NI sbRIO-9626 was mounted to a metal panel and oriented vertically, as shown in the following images.
- (B) Large Fiberglass Enclosure – The NI sbRIO-9626 was mounted to a metal panel and installed into a large fiberglass enclosure. The enclosure was oriented such that the PCB was vertical during testing, as shown in the following images.
- (D) Small Metal Enclosure – The NI sbRIO-9626 was mounted directly to the side wall of a small aluminum enclosure. The enclosure was oriented such that the PCB was vertical during testing, as shown in the following images.



Figure 7: Heat Spreader (NI P/N 153901-01)

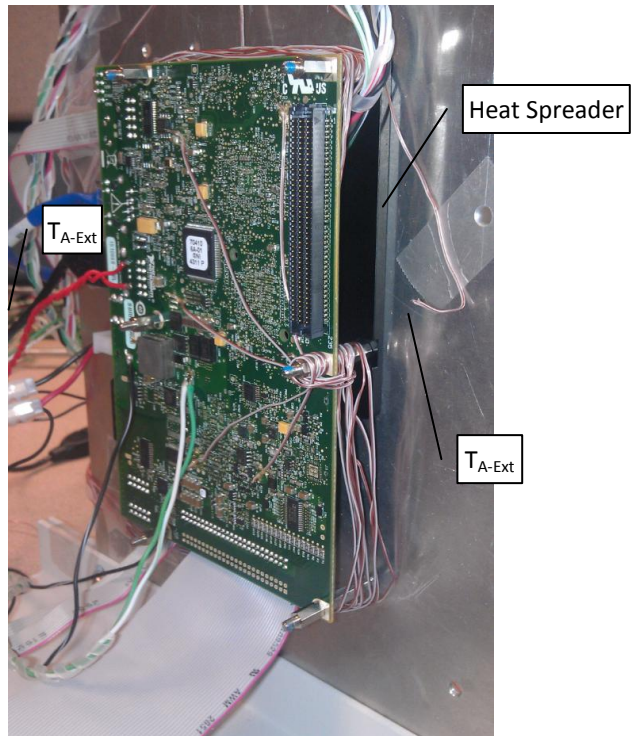


Figure 8: Configuration A – NI sbRIO-9626 in open air



Figure 9: Configuration B – NI sbRIO-9626 in a large fiberglass enclosure

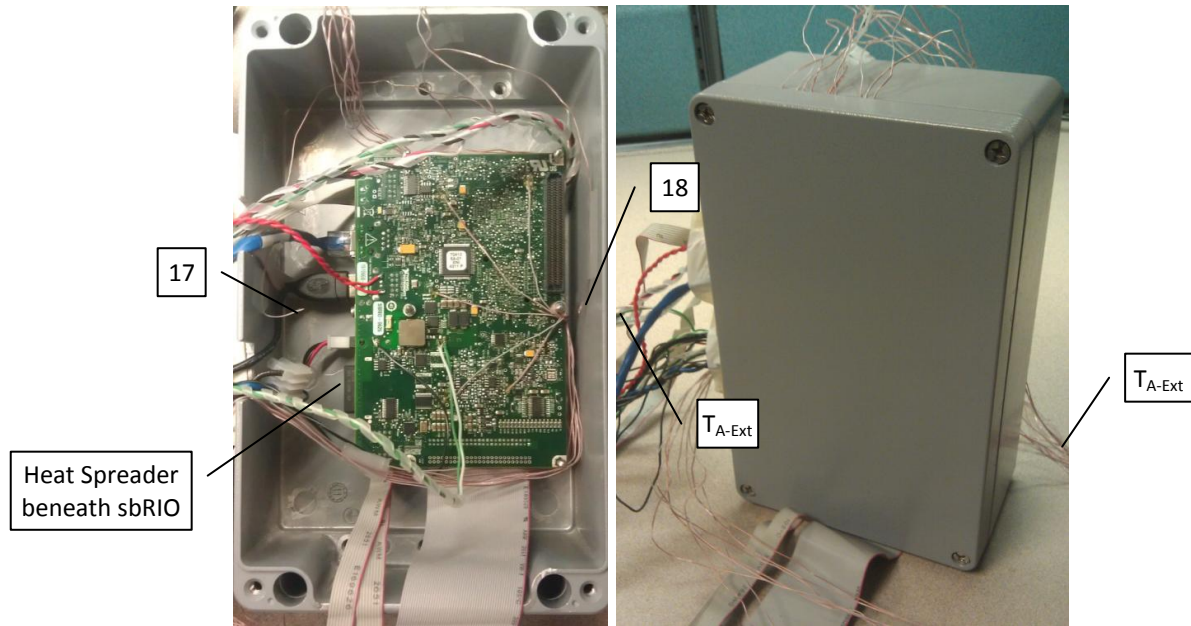


Figure 10: Configuration C – NI sbRIO-9626 in a small metal enclosure

4.4. Results

The following table shows the test results normalized to $T_{A-Ext}=25^{\circ}\text{C}$. In addition, it includes the margin of the temperature reading compared to the maximum allowed values for each component or ambient measurement. In the "margin" column, the lowest margin component is highlighted.

Channel	Name	A Open Air		B Large Fiberglass Encl.		D Small Metal Encl.	
		Measurement ($^{\circ}\text{C}$)	Margin ($^{\circ}\text{C}$)	Measurement ($^{\circ}\text{C}$)	Margin ($^{\circ}\text{C}$)	Measurement ($^{\circ}\text{C}$)	Margin ($^{\circ}\text{C}$)
1	T_{C-FPGA}	39.8	53.2	43.4	49.6	40.7	52.3
2	T_{C-Proc}	34.9	72.0	38.8	68.1	35.7	71.2
3	T_{C-DDR}	34.0	63.0	37.9	59.1	35.1	61.9
4	T_{C-NAND}	33.4	56.5	37.2	52.7	34.5	55.4
5	T_{A-P-TM}	35.8	49.2	39.4	45.6	38.9	46.1
6	T_{A-P-TR}	35.2	49.8	39.0	46.0	37.3	47.7
7	T_{A-P-BM}	36.1	48.9	40.2	44.8	39.7	45.3
8	T_{A-P-BR}	36.9	48.1	41.0	44.0	39.7	45.3
9	T_{A-S-TM}	35.4	49.6	39.2	45.8	39.0	46.0
10	T_{A-S-TR}	34.2	50.8	38.2	46.8	37.4	47.6
11	T_{A-S-BM}	36.0	49.0	39.8	45.2	39.8	45.4
12	T_{A-S-BR}	35.7	49.3	39.8	45.2	39.4	45.6
13	T_{A-P-TL}	35.2	49.8	38.3	46.7	38.6	46.4
14	T_{A-P-BL}	34.6	50.4	38.2	46.8	38.4	46.6
15	T_{A-S-TL}	34.9	50.1	38.1	46.9	38.8	46.2
16	T_{A-S-BL}	34.1	50.9	37.7	47.3	38.8	46.2
17	$T_{A-Encl-1}$	-	-	32.0	-	31.2	-
18	$T_{A-Encl-2}$	-	-	30.0	-	31.2	-
	T_{A-Ext}	25.0	-	25.0	-	25.0	-

The measured system power draw of the NI sbRIO-9626 was approximately 8.4W for each configuration.

With the addition of a heat spreader, the case temperature of the FPGA and other critical ICs are greatly reduced, resulting in the local ambient temperatures around the PCB becoming the lowest margin. Extrapolating to the maximum allowed local ambient temperature of the lowest margin region (T_{A-P-BR}), the estimated maximum achievable external ambient for each configuration is shown in the following table.

Configuration	A	B	D
Max Achievable T_{A-Ext} (°C)	73.1	69.0	70.3

The achievable external ambient temperatures are close together, showing that the addition of a heat spreader greatly reduces the impact of self-heating.

Finally, the heat spreader improved the thermal performance of the FPGA and other critical ICs such that less stressful applications will only see minimal additional improvements to the max achievable external ambient.

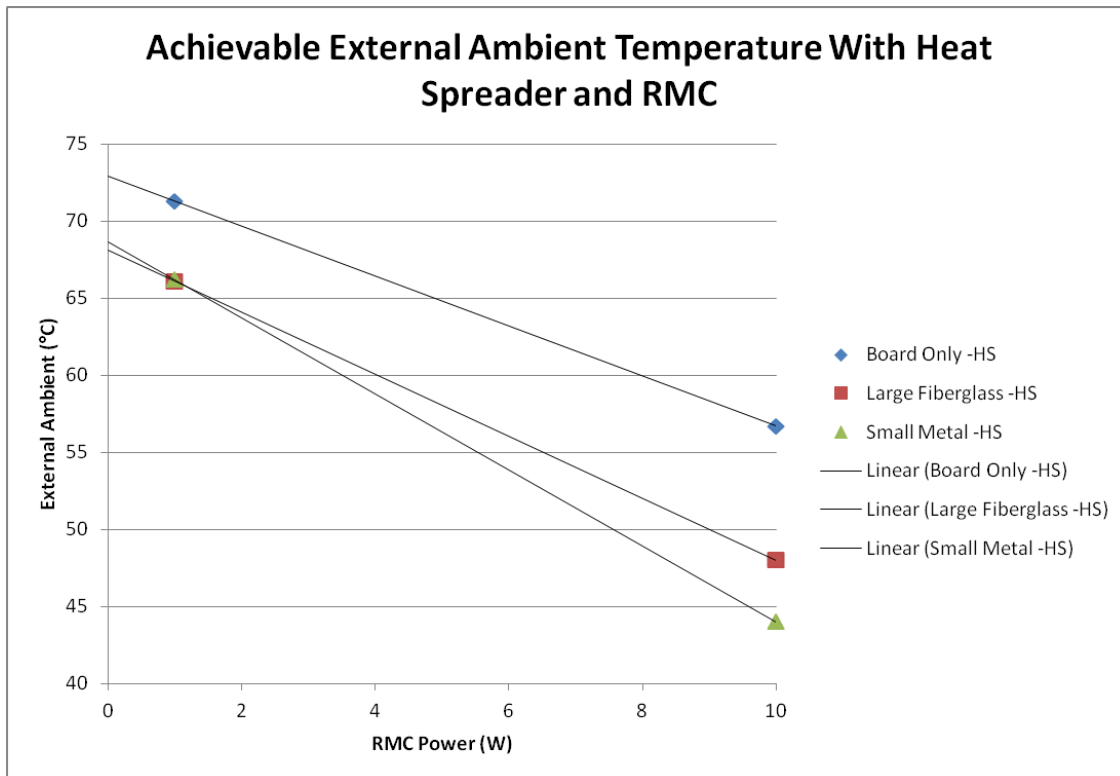
5. Example D – NI sbRIO-9626, Open Air vs. Enclosure Size, With Thermal Solution and RMC

5.1. Test Description

In this example, the NI sbRIO-9626 was configured with a heat spreader and an RMC loaded at varying power levels to show the impact of adding an expansion card. The same open air and enclosure configurations from Example C were used.

5.2. Test Results Summary

With the addition of a heat spreader, the impact of self-heating is greatly reduced compared to the tests in Example B. In addition, the enclosure size has much less effect, as the max achievable ambient of configurations B (large fiberglass enclosure) and D (small metal enclosure) are very close to each other and only minimally different from configuration A (open air). The heat spreader greatly reduces the case temperature of the FPGA and other critical ICs, making the local ambient temperatures around the PCB the lowest margin, resulting in a higher external ambient temperature. Extrapolating to the maximum allowed local ambient temperature of the lowest margin region, the estimated maximum achievable external ambient for each configuration is shown in the following chart.



Compared to Example B, configurations A and B result in approximately 10-16°C increase in the achievable external ambient, depending on the RMC power. Comparing configuration C (example B) to configuration D in this example there is approximately 17°C increase in the achievable external ambient by changing from a small plastic enclosure to a small metal enclosure with a heat spreader.

These configurations did not include a thermal solution on the RMC thermal load board. Adding a thermal solution to the RMC may result in additional improvements in the max achievable external ambient temperature.

5.3. Test Setup

In this example, the NI sbRIO-9626 was installed with a heat spreader (NI P/N 153901-01) and a resistor load RMC test board.

- The circuit cards were mounted such that the heat spreader on the NI sbRIO-9626 directly contacted the metal mounting surface.
- The RMC was mounted to the NI sbRIO-9626 using 9.65mm tall standoffs. No thermal solution was attached to the RMC load board.
- The same open air and enclosure configurations as in Example C were used.
- Tests were performed with the RMC load at 1W and 10W. In the test results, the subscript number for each test configuration corresponds to the RMC power load used for that test. So, A_1 corresponds to the 1W RMC, A_{10} corresponds to the 10W RMC, as so on.
- (A) Open Air Configuration – The NI sbRIO-9626 with RMC was mounted to a metal panel and oriented vertically, as shown in the following images.
- (B) Large Fiberglass Enclosure – The NI sbRIO-9626 with RMC was mounted to a metal panel and installed into a large fiberglass enclosure. The enclosure was oriented such that the PCBs were vertical during testing, as shown in the following images.
- (D) Small Metal Enclosure – The NI sbRIO-9626 was mounted directly to the side wall of a small aluminum enclosure. The enclosure was oriented such that the PCBs were vertical during testing, as shown in the following images.

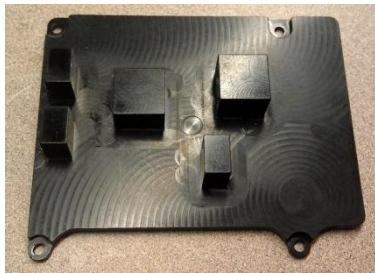


Figure 11: Heat Spreader (NI P/N 153901-01)

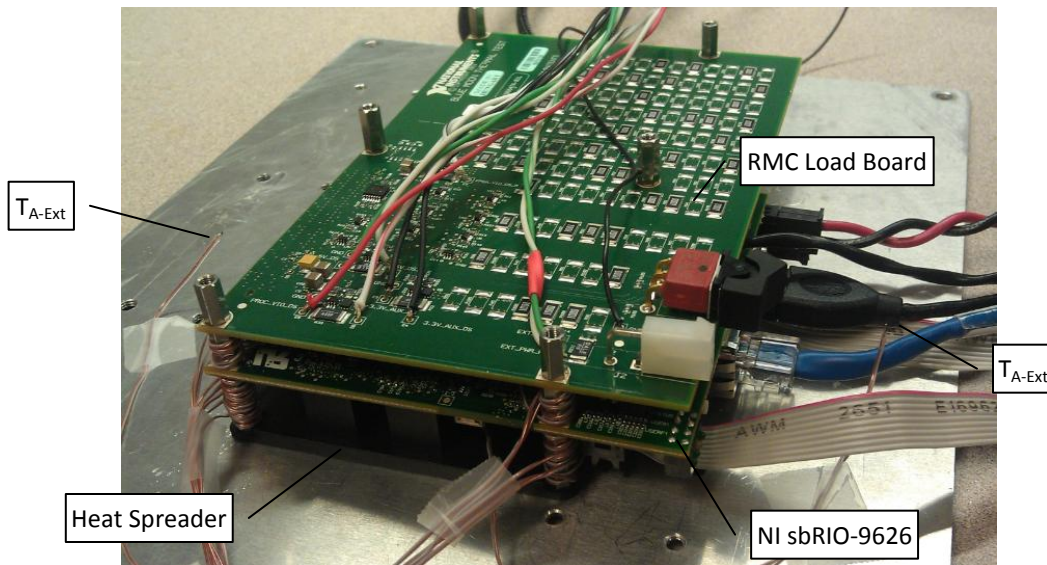


Figure 12: Configuration A – NI sbRIO-9626 with RMC test board in open air



Figure 13: Configuration B – NI sbRIO-9626 with RMC test board in a large fiberglass enclosure

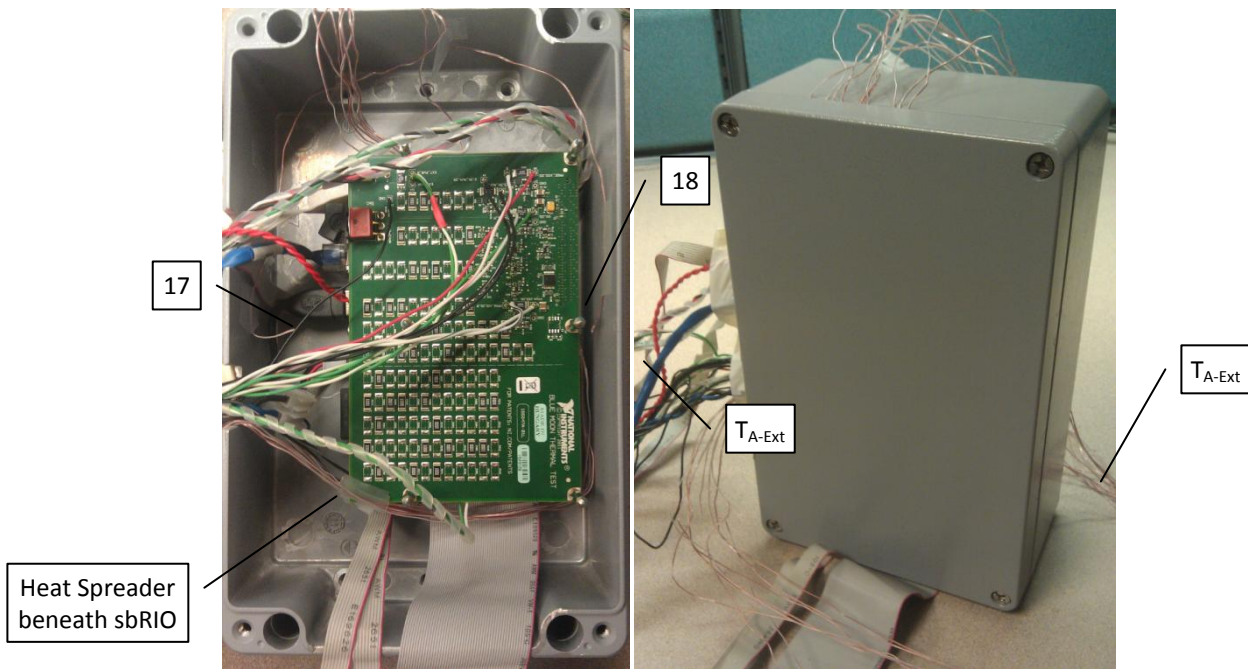


Figure 14: Configuration D – NI sbRIO-9626 with RMC test board in a small metal enclosure

5.4. Results

The following table shows the test results normalized to $T_{A-Ext}=25^{\circ}\text{C}$. It includes the power draw measured by both the sbRIO board and the RMC test board, along with the margin of the temperature reading compared to the maximum allowed values for each component or ambient measurement. In the "margin" column, the lowest margin component is highlighted.

Configuration A – Open Air with RMC

Configuration	A_1	A_{10}
NI sbRIO-9626 Power (W)	8.6	10.1
RMC Power (W)	1.0	10.0

Total System Power (W)		9.6		20.1	
Channel	Name	Measurement (°C)	Margin (°C)	Measurement (°C)	Margin (°C)
1	T _{C-FPGA}	40.3	52.7	46.3	46.7
2	T _{C-Proc}	35.4	71.5	40.3	66.6
3	T _{C-DDR}	34.7	62.3	39.8	57.2
4	T _{C-NAND}	34.0	55.9	39.5	50.4
5	T _{A-P-TM}	36.8	48.2	44.1	40.9
6	T _{A-P-TR}	36.0	49.0	43.6	41.4
7	T _{A-P-BM}	37.0	48.0	46.2	38.8
8	T _{A-P-BR}	37.8	47.2	44.9	40.1
9	T _{A-S-TM}	37.4	47.6	47.0	38.0
10	T _{A-S-TR}	36.6	48.4	46.5	38.5
11	T _{A-S-BM}	38.7	46.3	53.3	31.7
12	T _{A-S-BR}	37.7	47.3	48.4	36.6
13	T _{A-P-TL}	36.5	48.5	43.5	41.5
14	T _{A-P-BL}	35.9	49.1	43.1	41.9
15	T _{A-S-TL}	37.1	47.9	45.0	40.0
16	T _{A-S-BL}	36.6	48.4	46.0	39.0
	T _{A-Ext}	25.0	-	25.0	-

Configuration B – Large Fiberglass Enclosure with RMC

Configuration		B ₁		B ₁₀	
NI sbRIO-9626 Power (W)		8.6		10.1	
RMC Power (W)		1.0		10.0	
Total System Power (W)		9.6		20.1	
Channel	Name	Measurement (°C)	Margin (°C)	Measurement (°C)	Margin (°C)
1	T _{C-FPGA}	45.3	47.7	55.7	37.3
2	T _{C-Proc}	40.5	66.4	49.9	57.0
3	T _{C-DDR}	39.9	57.1	49.5	47.5
4	T _{C-NAND}	39.3	50.6	49.1	40.8
5	T _{A-P-TM}	41.5	43.5	52.8	32.2
6	T _{A-P-TR}	41.0	44.0	52.9	32.1
7	T _{A-P-BM}	42.9	42.1	56.8	28.2
8	T _{A-P-BR}	43.5	41.5	55.4	29.6
9	T _{A-S-TM}	41.8	43.2	55.1	29.9
10	T _{A-S-TR}	41.5	43.5	55.4	29.6
11	T _{A-S-BM}	43.9	41.1	62.0	23.0

12	T_{A-S-BR}	43.9	41.1	60.7	24.3
13	T_{A-P-TL}	40.6	44.4	50.7	34.3
14	T_{A-P-BL}	40.6	44.4	51.5	33.5
15	T_{A-S-TL}	41.3	43.7	53.0	32.0
16	T_{A-S-BL}	41.1	43.9	53.5	31.5
	T_{A-Ext}	25.0	-	25.0	-

Configuration D – Small Metal Enclosure with RMC

Configuration		D_1		D_{10}	
NI sbRIO-9626 Power (W)		8.6		10.2	
RMC Power (W)		1.0		10.0	
Total System Power (W)		9.6		20.2	
Channel	Name	Measurement (°C)	Margin (°C)	Measurement (°C)	Margin (°C)
1	T_{C-FPGA}	42.4	50.6	53.5	39.5
2	T_{C-Proc}	37.1	69.8	46.8	60.1
3	T_{C-DDR}	36.6	60.4	46.7	50.3
4	T_{C-NAND}	36.1	53.8	46.5	43.4
5	T_{A-P-TM}	41.2	43.8	56.2	28.8
6	T_{A-P-TR}	39.0	46.0	51.8	33.2
7	T_{A-P-BM}	42.5	42.5	59.9	25.1
8	T_{A-P-BR}	41.9	43.1	56.8	28.2
9	T_{A-S-TM}	41.7	43.3	59.1	25.9
10	T_{A-S-TR}	40.1	44.9	56.5	28.5
11	T_{A-S-BM}	43.8	41.2	66.0	19.0
12	T_{A-S-BR}	42.9	42.1	62.9	22.1
13	T_{A-P-TL}	41.0	44.0	55.1	29.9
14	T_{A-P-BL}	40.9	44.1	55.4	29.6
15	T_{A-S-TL}	41.9	43.1	57.7	27.3
16	T_{A-S-BL}	42.0	43.0	59.8	25.2
	T_{A-Ext}	25.0	-	25.0	-

The measured power draw of the NI sbRIO-9626 increases slightly as the RMC power increases due to the added load on the power supply. With a 10W RMC, this results in 1.5W additional power being dissipated on the sbRIO board.

The heat spreader greatly reduces the case temperature of the FPGA and other critical ICs, making the local ambient temperatures around the PCB the lowest margin.

It is also seen that the local ambient temperatures on the secondary side of the sbRIO board, between the sbRIO and RMC (T_{A-S-XX}) are typically hotter than the local ambient temperature measurements on the primary side. This becomes more noticeable as the RMC power increases.

Using this data, the maximum achievable external ambient for each configuration is estimated, as shown in the following table.

RMC Power (W)	Max Achievable T_{A-Ext} (°C)		
	A	B	D
1.0	71.3	66.1	66.2
10.0	56.7	48.0	44.0

The following chart plots the achievable external ambient compared with RMC power levels for each configuration. The results may be approximated with a linear extrapolation to estimate the ambient at different RMC power levels within the different enclosures.

